

SIDC50D60C6

Fast switching diode chip in EMCON 3 -Technology

FEATURES:

٠

•

- 600V EMCON 3 technology 70 µm chip
- soft, fast switching • low reverse recovery charge

small temperature coefficient

- This chip is used for:
- power module •



Applications:

• drives

Chip Type	V _R	l _F	Die Size	Package
SIDC50D60C6	600V	200A	9.2 x 5.44 mm ²	sawn on foil

MECHANICAL PARAMETER:

Raster size	9.2 x 5.44				
		2			
Area total / active	50.05 / 44.47	mm ²			
Anode pad size	8.52 x 4.74				
Thickness	70	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	282 pcs				
Passivation frontside	Photoimide				
Anode metallization	3200 nm AlSiCu				
Cathode metallization	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500µm				
Reject ink dot size	Ø 0.65mm; max 1.2mm				
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



SIDC50D60C6

Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	V _{RRM}		600	V
Continuous forward current limited by	1_		1)	
T _{jmax}	1 _F			А
Maximum repetitive forward current	1		400	~
limited by T _{jmax}	IFRM		400	
Operating junction and storage temperature	T_{j} , T_{stg}		-40+175	°C

¹⁾ depending on thermal properties of assembly

Static Electrical Characteristics (tested on chip), T_j =25 °C, unless otherwise specified

Parameter	Symbol	Cond	Value			Unit	
Falameter	Symbol	Cond	nions	min.	Тур.	max. 27	Onic
Reverse leakage current	I _R	V _R =600V	$T_j=25 °C$			27	μA
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	<i>T_j</i> =25°C	600			V
Forward voltage drop	V _F	I _F =200A	$T_j=25 °C$	1.2	1.6	1.9	V

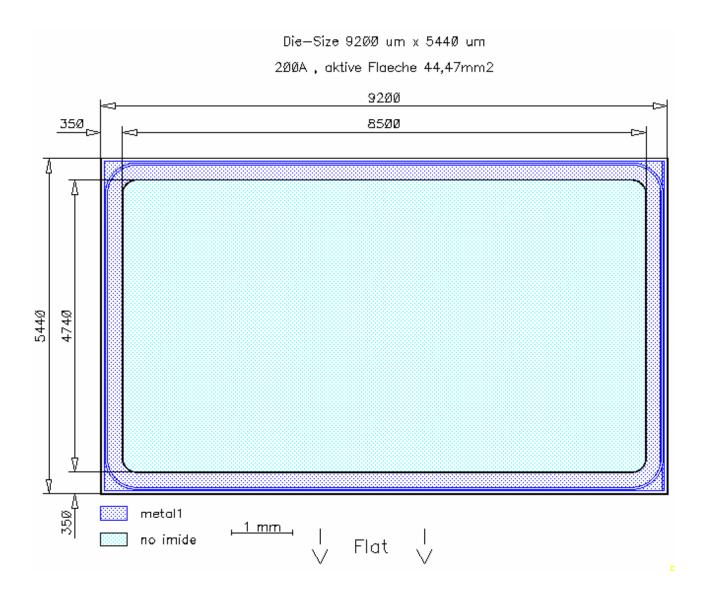
Dynamic Electrical Characteristics (verified by design/characterization), inductive load

Parameter	Symbol	Condi	Value ²⁾			Unit	
Falailletei	Symbol	Conai	min.	Тур.	max.	Unit	
Peak reverse recovery current	I _{RM}	$I_F=200A$ di/dt=5700A/ms $V_R=300V$ $V_{GE}= -15V$	$T_j = 25 \ ^\circ C$ $T_j = 125 \ ^\circ C$ $T_j = 150 \ ^\circ C$		160 230 240		A
Recovered charge	Q _r	$I_F=200A$ di/dt=5700A/ms $V_R=300V$ $V_{GE}= -15V$	$T_j = 25 \ ^\circ C$ $T_j = 125 \ ^\circ C$ $T_j = 150 \ ^\circ C$		10.0 17.0 20.0		μC
Reverse recovery energy	E _{rec}	$I_F = 200A$ di/dt = 5700A/ms $V_R = 300V$ $V_{GE} = -15V$	$T_j = 25 \ ^\circ C$ $T_j = 125 \ ^\circ C$ $T_j = 150 \ ^\circ C$		3.00 5.20 5.80		mJ

²⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





SIDC50D60C6

FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

FS200R06KE3

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2006. All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.